



We3H-3

Using a 3D-Printed Waveguide Filter with Ridge Resonators as a Dielectric Permittivity Sensor

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Outline



Slanted ridge resonators

• Dielectric measurement principle

Multiple slanted ridges

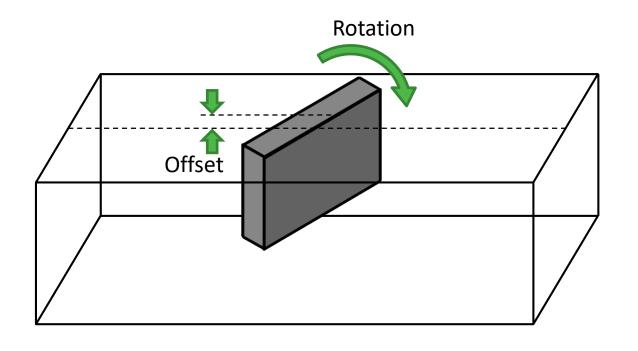
Multiple slanted ridge dielectric sensor



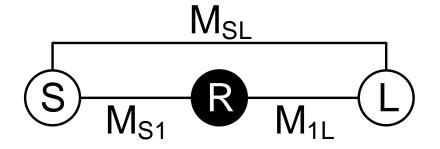


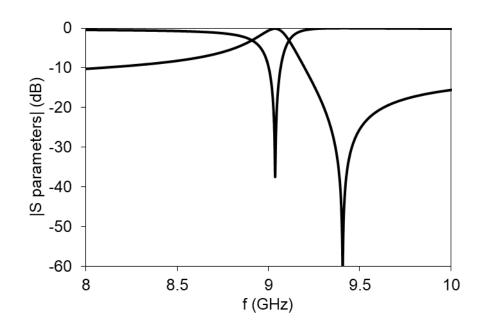
Slanted ridge resonators





- Compact structure
- Doublet frequency response



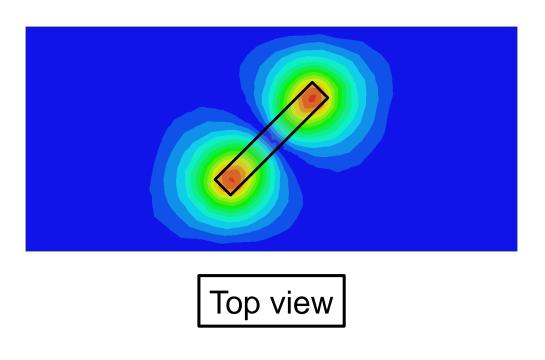


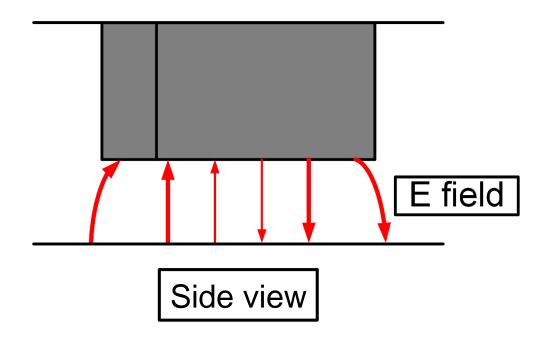




Slanted ridge resonators





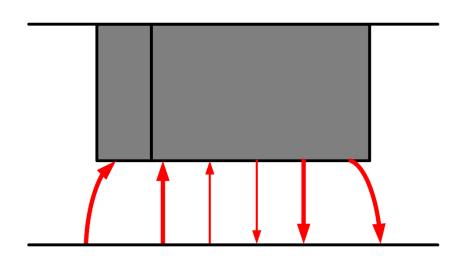


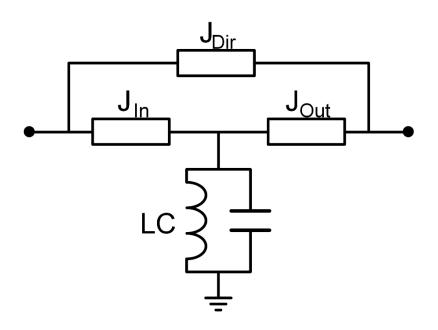
- Electric field distribution
- Strong vertical components below the ridge









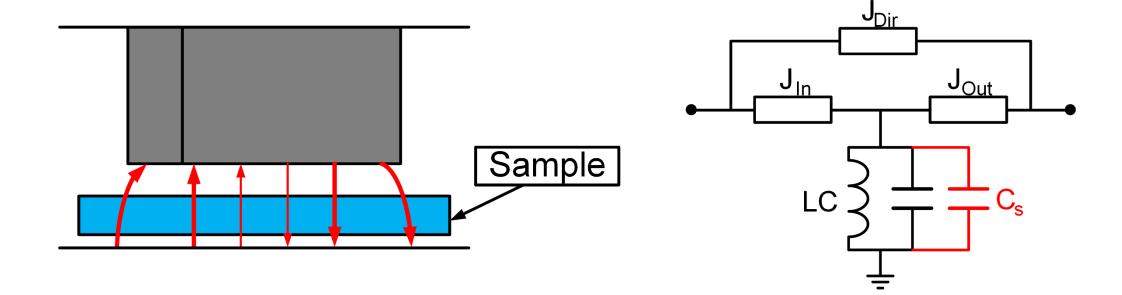


Unperturbed state







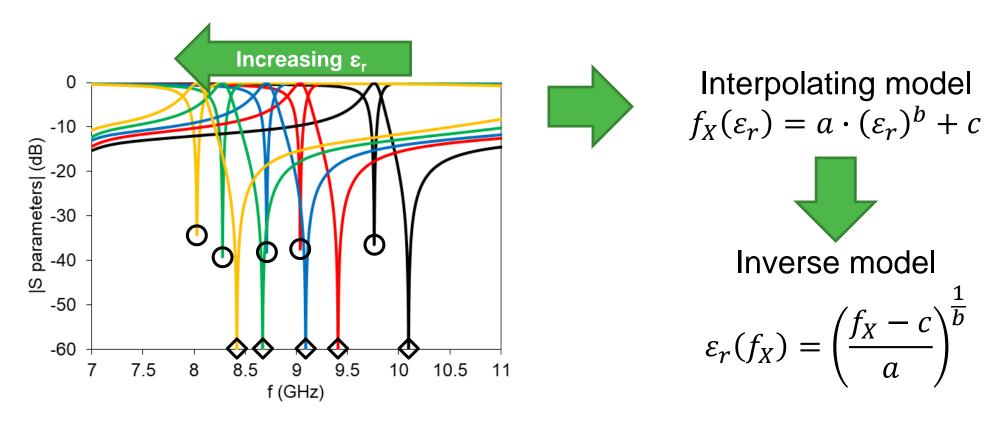


- Dielectric sample loading
- Shift in the resonance







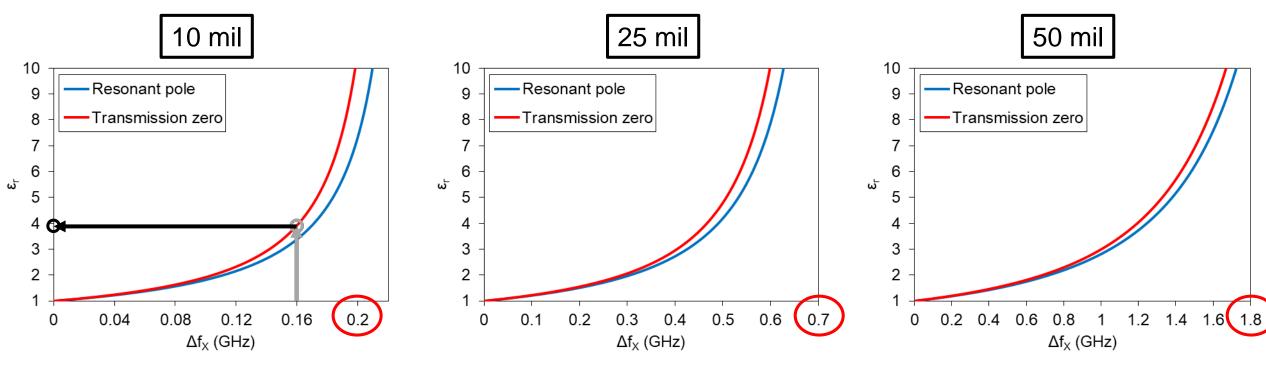


Model for frequency shift of resonant pole or transmission zero







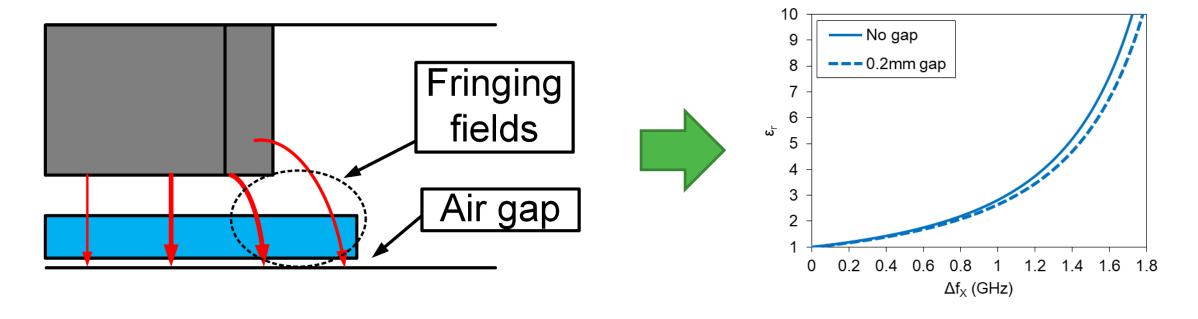


- Different sample thicknesses have different sensitivity
- A model can be made for each situation







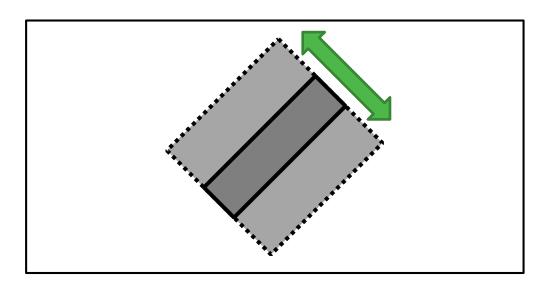


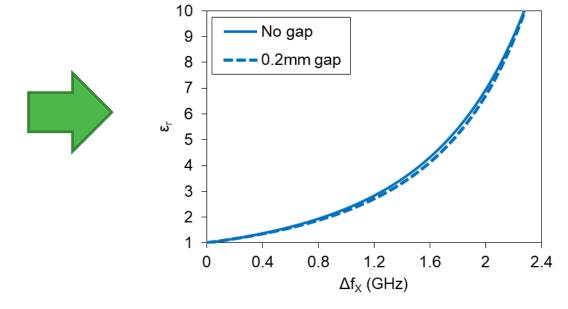
- Fringing fields shape makes the setup sensitive to positioning errors
- Air gap below the sample

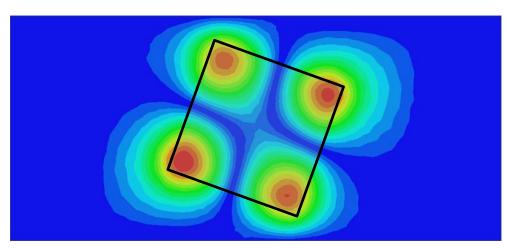










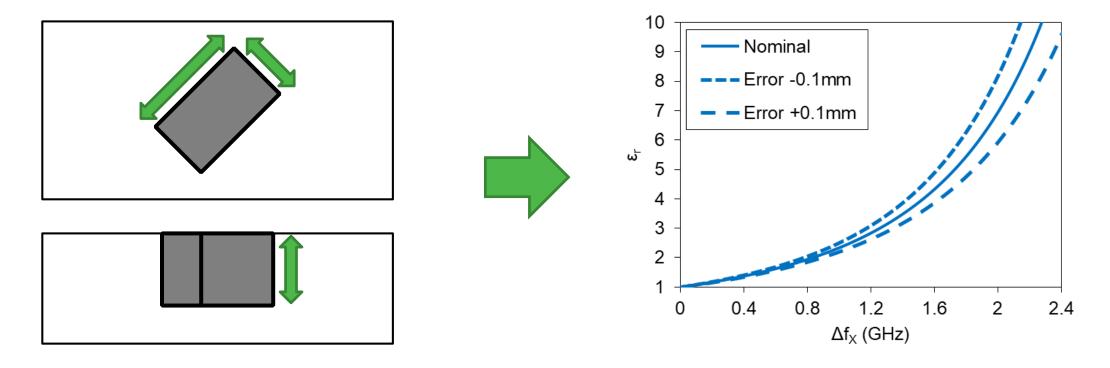


- Effect mitigated by increasing capacitive load
- Thicker iris with high order mode







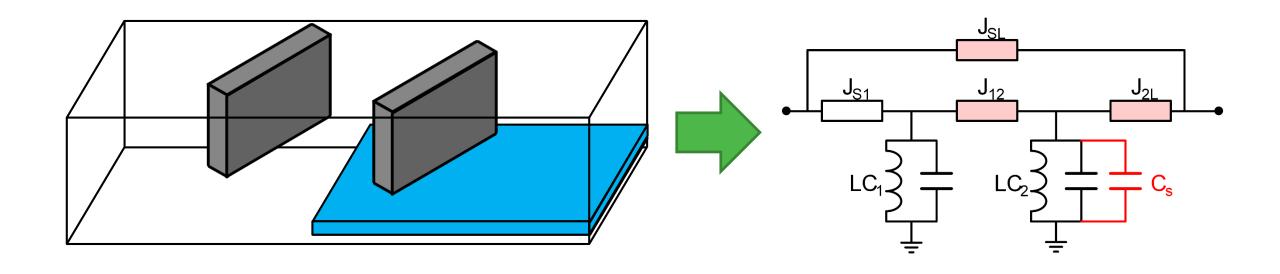


- Fabrication imperfections lead to uncertainties
- Important with low cost fabrication methods (additive manufacturing)







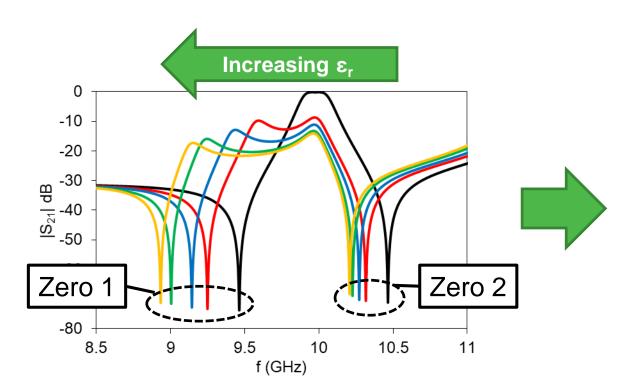


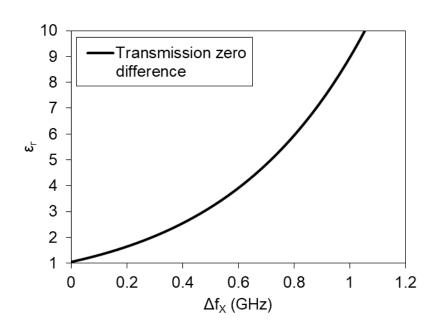
- Sample placed under one of the irises
- Other resonator is mostly unloaded











- Dielectric loading strongly shifts lower frequency zero
- Upper frequency zero less affected
- $\Delta f = f_{z2} f_{z1}$

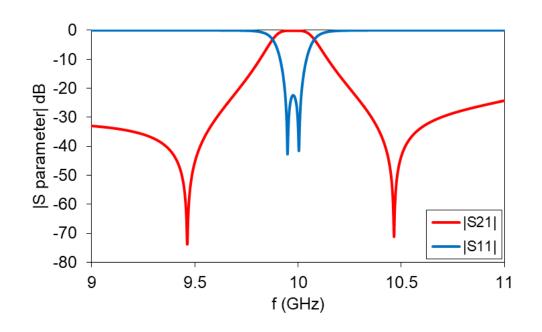










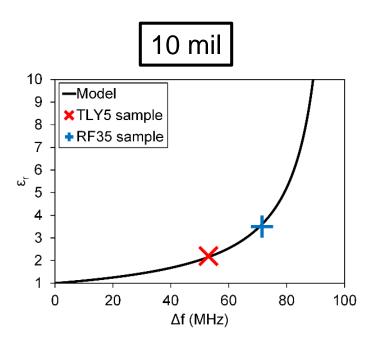


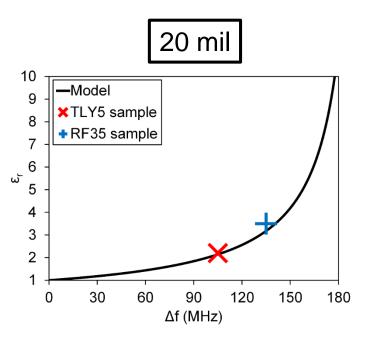
- Test measurements done on a previously designed filter [1]
- Two transmission zeroes
- [1] F. Romano, N. Delmonte, C. Tomassoni, L. Perregrini, and M. Bozzi, "3D-Printed Compact Waveguide Filters Based on Slanted Ridge Resonators," IMS 2022, Denver, CO, USA, 19-24 June 2022

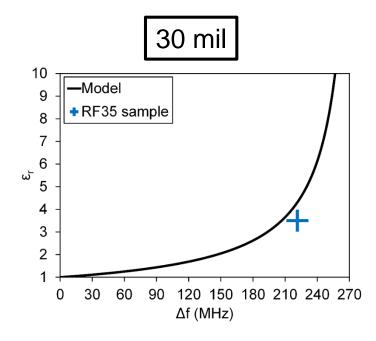










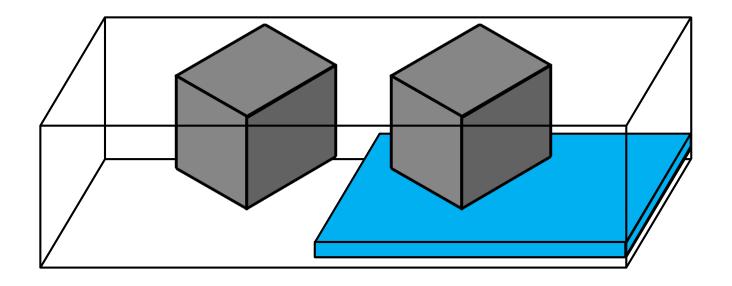


Dielectric material	Nominal ϵ_{r}	Sample thickness	Retrieved ϵ_{r}	Error
TLY5	2.2	10 mil	2.16	-2%
		20 mil	2.14	-2.6%
RF35	3.5	10 mil	3.6	+3%
		20 mil	3.18	-9.2%
		30 mil	3.73	+6.5%









Multiple thick irises to improve sensitivity vs air gap





Conclusion



Compact slanted ridge structures for dielectric sensing

Ridge dimension optimization improve resilience vs sample position error

Multiple ridges allow for differential measurement

